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OSP-17267

DT01 Rec'd PCT/PTO 07 FEB 2005

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Kanno et al.  
Serial No.: Herewith  
Filed: Herewith  
Group Art Unit: Unknown  
Examiner: Unknown  
Title: WAFER ROTATING DEVICE AND EDGE FLAW INSPECTION  
DEVICE PROVIDED THEREWITH

**PRELIMINARY AMENDMENT**

Mail Stop PCT  
Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Please amend the application in the following particulars prior to Examination.